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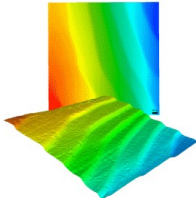
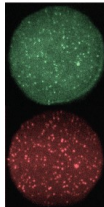
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## ABSTRACT

The high-bandwidth preamplifier is a vital component designed to increase the scanning speed of a high-speed scanning tunneling microscope (STM). However, the bandwidth is limited not only by the characteristic  $G\Omega$  feedback resistor  $R_F$  but also by the characteristic unity-gain-stable operational amplifier (UGS-OPA) in the STM preamplifier. Here, we report that paralleling a resistor with the tunneling junction (PRTJ) can break both limitations. Then, the UGS-OPA can be replaced by a higher rate, higher antinoise ability, decompensated OPA. By doing so, a bandwidth of more than 100 MHz was achieved in the STM preamplifier with decompensated OPA657, and a higher bandwidth is possible. High-clarity atomic resolution STM images were obtained under about 10 MHz bandwidth and quantum point contact microscopy mode with a record-breaking line rate of 50 k lines/s and a record-breaking frame rate of 250 frames/s. Both the PRTJ method and the decompensated OPA will pave the way for higher scanning speeds and play a key role in the design of high-performance STMs.

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## I. INTRODUCTION

The scanning tunneling microscope (STM) with high-speed (HS) scanning capability is a crucial tool in surface science and technology.<sup>1–5</sup> It has revealed the mechanism of dynamic phenomena at the atomic scale: the growth mechanism of graphene,<sup>4</sup> for example. Inevitably, it will also be a tool for high-speed readout in atomic-scale data storage devices.<sup>3</sup> The femtosecond (fs) laser STM<sup>6</sup> and electronic pump-probe radio STM can only investigate dynamic processes with a spectrum, but their imaging speeds are also conventional.<sup>7</sup> Accordingly, many groups are devoting themselves to the development of high-speed imaging STMs.<sup>8–12</sup>

However, progress in this direction is greatly restricted by not only the limited bandwidth  $f_B$  but also the bad signal-to-noise ratio (SNR) in STM preamplifiers.<sup>4,13–16</sup>

The bandwidth is limited by several factors simultaneously. First,  $f_B \leq (2\pi R_F C_F)^{-1}$ , where  $R_F$  is the feedback resistance and  $C_F = (C_{AF} + C_{SF})$ ; in the latter,  $C_{AF}$  is from an artificially added feedback capacitor and  $C_{SF}$  is the unavoidable stray capacitance in the feedback loop wiring.<sup>17</sup> Specific methods to increase  $f_B$  include connecting many small resistance feedback resistors in series and multi-stage amplifying.<sup>8</sup> Second,  $f_B$  is also limited by  $f_B \leq GBP/G$ , where  $GBP$  is the gain bandwidth product of the operational amplifier (OPA) and  $G$  is the noise gain of the amplifying circuit. This formula

indicates that an OPA with higher GBP is required in the HS-STM preamplifier. Third, the STM preamplifier is a trans-impedance amplifier (TIA), while the preamplifier of the alternating current (AC)-STM belongs to the voltage amplifier.<sup>18</sup> Then, the bandwidth theory of TIA, which requires  $f_B \leq (GBP/2\pi R_F C_S)^{1/2}$ , has to be taken into account, where  $C_S = C_{CM} + C_{DIFF} + C_j$  is the total source capacitance,<sup>19,20</sup>  $C_{CM}$  and  $C_{DIFF}$  separately are the common mode and differential mode input capacitance, and  $C_j$  ( $\approx 0.2$  pF) is the tip-sample junction capacitance.<sup>20</sup> None of these bandwidth limitations can be ignored.

The authors have decreased the  $R_F$  from  $\sim G\Omega$  to  $10 M\Omega$  without the help of  $C_{AF}$ , and excellent STM images have been obtained,<sup>11,21</sup> but the bandwidth was only a little more than 10 kHz. The authors have also tried a  $10 k\Omega$  order  $R_F$ , which is frequently used in point contact mode STM/SPSTMs with several  $G_0$  conductance<sup>22–24</sup> or  $\mu A$  tunneling current<sup>22,25,26</sup> ( $\sim 12.9 k\Omega$  tunneling resistance<sup>24</sup>), to further increase the bandwidth. However, self-sustained oscillation (SSO) happens when the OPA model is OPA627 and there is no  $C_{AF}$ . Even more unfortunately, no phase compensation method is known to delete the SSO without a bandwidth cost, no matter internal compensation or external compensation.<sup>27</sup> The method of internal compensation by emitter degeneration, which is achieved by connecting a resistor in the emitter of the differential input stage of an OPA, will decrease the open-loop gain  $A_{OL}$  that indicates the superiority of the OPA. Internal dominant pole compensation, which is achieved by setting a capacitor in the intermediate stage, will decrease the GBP. External compensation by one-capacitor or two-capacitor is only suitable for voltage amplifiers. Limited by the above restrictions, the final bandwidth of the first stage (or the total) STM preamplifier is no more than 1 MHz. The highest frame frequency achieved is no more than 246 Hz,<sup>9</sup> and the highest line frequency is no more than 26 kHz<sup>11</sup> with poor atomic resolution.<sup>11,28</sup>

In this paper, the unique electronics property of the STM preamplifiers is analyzed. It varies at the different stages of the STM measurement. Then, the idea of paralleling a resistor with the tunneling junction (PRTJ) to delete the SSO is presented. This method results in the noise gain of the STM preamplifier increasing from unity to dozens. Counterintuitively, this increase is a good thing since it means that a high-rate, decompensated OPA with better antinoise ability can be used in the STM preamplifier. Finally, with the help of PRTJ and the decompensated OPA, up to 100 MHz ultrahigh bandwidth is achieved in the STM preamplifier, which is better than existing methods.<sup>8,15,17</sup> High-clarity, atomic-resolution quantum point contact microscopy (QPCM) imaging is achieved with record-breaking line frequency and frame frequency. QPCM is excellent in chemical sensitivity<sup>22</sup> and can be used to hear the audio

frequency atom manipulation “sound” and investigate the origin of this “sound” better.<sup>23</sup>

## II. PRINCIPLES AND DESIGN

### A. Electronic properties of the STM preamplifier

The tip apex of the probe is far away from the sample initially in each STM measurement. Then, the coarse approach (CA) process is required, which makes the tip-sample distance smaller and smaller until the tunneling current is measurable. During this stage, the equivalent resistance  $r_{jCA}(t)$  of the tunneling junction is close to  $\infty$ , and almost no tunneling current can be detected at this CA stage. This is a typical unstable state in electronics in which the noise gain  $G = (1 + R_F/\infty) \sim 1$ ; this is called the *unity-gain* state. Unfortunately, the CA stage has seemed inevitable in STM measurements up to now.

The process following the CA stage is the scanning tunneling (ST) stage. The equivalent resistance  $r_{jST}(t)$  of the tunneling junction is usually much less than the resistance  $R_F$ . Then, the noise gain of the STM preamplifier usually is dozens, which results in the STM preamplifier being in a normal TIA state.

### B. Unity gain stable amplifiers

The unstable unity-gain state requires a special unity-gain-stable (UGS) OPA under current STM preamplifier technology. UGS-OPA is a performance-compromised version of an OPA, designed for barely sufficient stability by complete compensation by the decompensated OPA. The UGS-OPA and decompensated OPA mostly appear in pairs.<sup>27,30,31</sup> The decompensated OPA has almost all the advantages over the UGS-OPA except that the hash required a minimum noise gain  $G_{min}$ . For example, higher GBP, higher slew rate (SR), and less settling time (ST) indicate the speed superiority of the decompensated OPA. The higher open-loop gain  $A_{OL}$ , less total harmonic distortion and noise (THD + N), higher common-mode rejection ratios (CMRR), and the higher maximum output voltage  $u_{omax}$  indicate the other superiority of the decompensated OPA. As an example, OPA627 (a UGS-OPA) and OPA637 (a decompensated OPA) are compared, as shown in Table I. The bottom line of the first line of the table is the test conditions. OPA637 is dozens of times better than OPA627 in multiple indicators. It is a huge loss that decompensated OPAs could not be used in STM preamplifiers before now, especially in HS-STMs.

### C. STM preamplifier designs

SSO happens when both the amplitude condition and the phase condition are satisfied in the STM preamplifier at the same time,

TABLE I. Advantages of decompensated OPA over UGS-OPA, taking OPA627 and OPA637 as examples.

| Type of OPA              | GBP (MHz) |       | SR (V/ $\mu s$ ) | ST ( $\mu s$ ) | $A_{OL}$ (dB) | THD + N (ppm) | CMRR (dB) | $u_{omax}$ (V) | $G_{min}$ |
|--------------------------|-----------|-------|------------------|----------------|---------------|---------------|-----------|----------------|-----------|
|                          | 25 °C     | 25 °C |                  | $G = -10$      | 20 kHz        | 20 kHz        | 20 kHz    | 7 MHz          |           |
| OPA627BP (UGS type)      | 16        | 16    |                  |                | 23            | 50            | 100       | 3              | 1         |
| OPA637BP (Decompensated) | 80        | 99    |                  |                | 34            | 10            | 120       | 6              | 5         |

regardless of whether the OPA is UGS.<sup>27,32</sup> In this situation, the minimum noise gain requirement of the picky decompensated OPA inversely indicates that increasing the noise gain can make the STM preamplifier more stable.<sup>30</sup>

A resistor is connected in parallel with the tunneling junction to increase the noise gain of the STM preamplifier. The bias voltage  $U_B$  can be set in multiple ways, one of which is shown in Fig. 1. To better characterize the tunneling junction to be measured, the resistor mentioned above has to have constant resistance, noted as  $R_0$ .

The noise gain will increase from 1 to  $(1 + R_F/R_0)$  at the CA stage because of the parallel resistor configuration, which we denote by  $r_j(t)/R_0$ . This means that UGS-OPAs are no longer required. Instead, decompensated OPAs can be used not only to increase the  $f_B$  but also to augment the antinoise ability in the STM preamplifier, as shown in Fig. 1.

The output  $u_O(t)$  of this  $r_j(t)/R_0$  STM preamplifier can be divided into two parts  $u_{OSTM}(t)$  and  $U_{OR0}$  in theory by the superposition theorem:  $u_O(t) = u_{OSTM}(t) + U_{OR0}$ . Constant  $U_{OR0} = U_B \times (1 + R_F/R_0)$  is caused by the constant current  $I_{R0}$ , which flows through the constant resistor  $R_0$ , as shown in Fig. 1. This  $U_{OR0}$  value is independent of what sample is scanned, so it can be deleted to increase the contrast of the sample signal. The  $u_{OSTM}(t)$ , which is caused by the tunneling current  $i_j(t)$  that flows through the tunneling junction  $r_j(t)$ , is the same as the output of a traditional STM preamplifier, as shown in Fig. 1. The bad effect of the thermal noise current in the constant resistance  $R_0$  will be analyzed in Sec. II D.

#### D. SNR analysis of the $r_j(t)/R_0$ STM preamplifier

The thermal noise current caused by the constant resistance  $R_0$  can be calculated by  $i_{nR0} = (4kTf_B/R_0)^{1/2} = 1.62 \times 10^{-4}/(R_0R_F)^{1/2}$ , where  $k = 1.38 \times 10^{-23}$  J/K,  $T \approx 300$  K, and  $f_{Bmax} = 1/2\pi R_F C_{SF} \approx 1.6 \times 10^{12}/R_F$  for  $C_{SF} \approx 0.1$  pF<sup>21</sup>. If  $R_F/R_0 = N$ , then  $i_{nR0max} = 1.62 \times 10^{-4} \times N^{1/2}/R_F$ , where  $N$  is a constant. The signal of the STM output mentioned above can be ideally expressed as simple harmonic  $u_{OSTM}(t) = U_A \sin 2\pi ft + U_C$ , while the frequency  $f$ , amplitude  $U_A$ , and offset  $U_C$  may vary when the STM tip apex is scanning from one atom to another atom.

The only part that reflects the resolution of the STM is the AC component  $U_A \sin 2\pi ft$ . Then, the effective value of the tunneling current  $i_j(t)$  can be expressed as  $i_j(t) = U_A/\sqrt{2}R_F$ . The negative effect

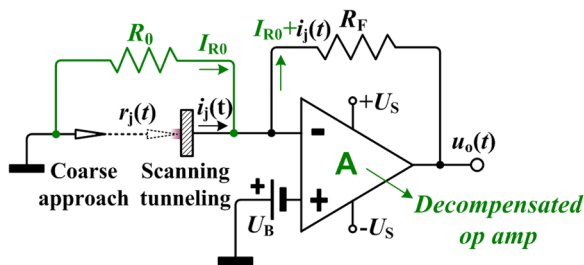


FIG. 1. Schematic diagram of the  $r_j(t)/R_0$  STM preamplifier.  $r_j(t)$  represents the equivalent resistance of the tunneling junction.  $U_B$  is the bias voltage. The  $\pm U_S$  are the positive and negative power supplies. A decompensated operational amplifier is used in the STM preamplifier. The gradually changing shadow between the tip and sample illustrates the trend of the tunneling probability.

of  $R_0$  on the SNR can be calculated as  $SNR_{R0min} = (U_A/\sqrt{2}R_F)/i_{nR0max} = 4.4 \times 10^3 \times N^{-1/2} U_A$ . Because  $N$  is usually about 10, the fact that 100 mV  $U_A$  is moderate in most STM measurements will make the SNR rise to about 100. When operated under LHe temperature, the SNR will increase tenfolds. The higher CMRR, higher  $A_{OL}$ , and lower THD + N of the decompensated OPA compared to the traditional UGS-OPA will further ensure the high SNR.

### III. RESULTS AND DISCUSSION

#### A. Higher stability STM preamplifier

The stability of our  $r_j(t)/R_0$  STM preamplifier was verified first with a traditional UGS-OPA. The results are measured with a Tektronix TDS 3014C oscilloscope. SSO happens at about 90 kHz when OPA627 and a 1 M $\Omega$  feedback resistance  $R_F$  is used. The wave resembles a square wave and is caused by the over saturated output of a sine wave, which is chopped, as shown in Fig. 2. The amplitude is so high that the scale rises to 3 V, as shown on the left side. The peak-to-peak value is still as high as about 13 V after being chopped, which means that no signal can be amplified and output in the conventional STM preamplifier circuit.

When a 100 k $\Omega$   $R_0$  is introduced, SSO is eliminated. Then, a voltage amplifier is formed at the CA stage with no measurable tunneling current. The output is so small that the scale is only 0.1 V, as shown in Fig. 2 on the right-hand side. The straight horizontal line output is mainly caused by the offset of the  $r_j(t)/R_0$  STM preamplifier. No special shock absorption and electromagnetic shielding are needed, except that the STM preamplifier circuit box is made of cast aluminum. The alternating current component has strength no more than 10 mV, which is the noise of the system.

The phase compensation achieved by the single resistor  $R_0$  is different from the existing compensation methods, both internally and externally.<sup>27</sup> It can also be used in other TIAs to increase their stability.

#### B. Radio frequency bandwidth STM preamplifier

Decompensated OPAs, such as OPA637 or OPA657, can be introduced into the STM preamplifier to achieve higher bandwidth and higher SNR for the first time, benefiting from the highly stable  $r_j(t)/R_0$  design.<sup>21</sup> The higher stability enables the  $R_F$  value to

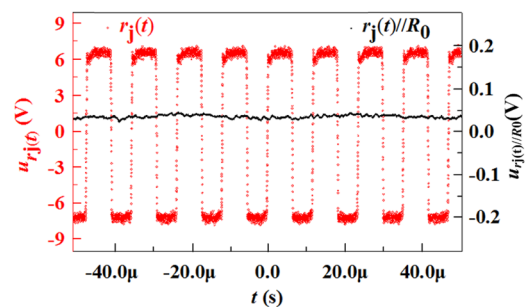


FIG. 2. Comparison of stability between the traditional and  $r_j(t)/R_0$  STM preamplifier. Both waves are characterized using an oscilloscope.

decrease from 1 M $\Omega$  to 10 k $\Omega$ , which further increases the  $f_B$ . The resistor  $R_0$  in both circuits has resistance 1 k $\Omega$ .

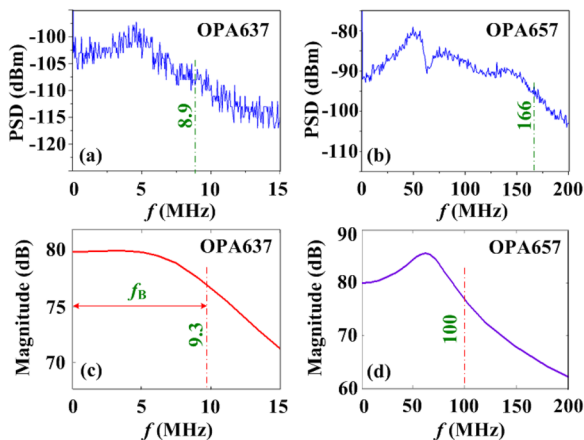
Power spectral density measurements are used to characterize the bandwidth, as shown in Figs. 3(a) and 3(b). The bandwidths are about 8.9 MHz and 166 MHz. The three peaks in Fig. 3(b) may be caused by the potential instability in the corresponding frequency. The ultrahigh 166 MHz  $f_B$  fits well with both the theory of  $f_B = (2\pi R_F C_{SF})^{-1} = 159$  MHz and the theory of  $f_B \leq \text{GBP}/G \approx 145$  MHz, where the GBP of OPA657 is 1.6 GHz.

Both bandwidths are also analyzed by the Bode diagram of the  $r_j(t)/R_0$  STM preamplifier under the single-pole OPA model and the  $A_{OL} \gg 1$  assumption.<sup>19</sup> When  $R_0$  is introduced, the total input impedance changes from  $X_{CS}$  to  $X_{CS}/R_0$ . However, the expression of the transfer function of the STM preamplifier<sup>19</sup> is still intact:  $u/i = \omega_0^2 R_F / (s^2 + s\omega_0/Q + \omega_0^2)$  with intact  $\omega_0^2 = 2\pi \text{GBP} / [R_F(C_F + C_S)]$ , where  $s = i\omega$ . Only the expression of the quality factor  $Q$  changed slightly, by  $R_F/R_0$ , into

$$Q \approx [2\pi \times \text{GBP} \times R_F \times (C_F + C_S)]^{1/2} / (1 + R_F/R_0 + 2\pi \times \text{GBP} \times R_F \times C_F).$$

When OPA637 is used,  $Q$  and  $\omega_0$  are about 0.76 rad/s and 57.4 rad/s, respectively; when OPA657 is used,  $Q$  and  $\omega_0$  are about 1.12 rad/s and 428 rad/s, respectively. Substituting each  $Q$  and  $\omega_0$  into the transfer function, we get  $u/i_{\text{OPA637}} = 3.28 \times 10^{19} / (s^2 + 7.52 \times 10^7 s + 3.28 \times 10^{15})$  and  $u/i_{\text{OPA657}} = 1.8 \times 10^{19} / (s^2 + 2.3 \times 10^8 s + 1.8 \times 10^{17})$ . The magnitude parts of each transfer function indicate that the bandwidths are about 9.3 MHz and 100 MHz, as shown in Figs. 3(c) and 3(d). The bandwidth of 9.3 MHz is in good agreement with the data in Fig. 3(a). We note that 100 MHz is less than 166 MHz; the lower value may result from the crude assumption of the single-pole OPA model, as shown by the single pole in Fig. 3(d).

The frequency 166 MHz  $f_B$  is so high that it becomes a challenge for other parts of the HS-STM system, such as the scanner and data acquisition (DAQ) card.<sup>9</sup> The DAQ card in our HS-STM system is a



**FIG. 3.** Power spectral density measurements and Bode diagrams of  $r_j(t)/R_0$  STM preamplifiers. (a) and (b) are the PSD measurements. (c) and (d) are the Bode diagrams. (a) and (c) are the output measured and calculated for the STM preamplifier based on OPA637. (b) and (d) are the output measured and calculated for the STM preamplifier based on OPA657.

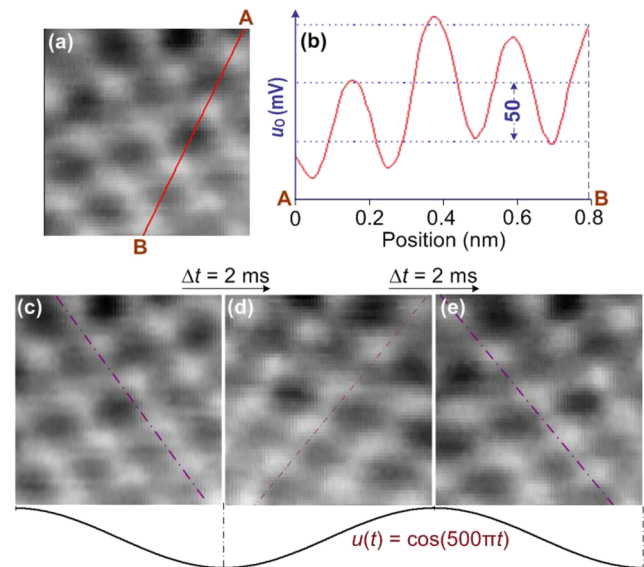
PXI-6124 whose sampling rate is 4 MS/s. The resonant frequency of the scanner is about 100 kHz.

### C. Quantum point contact mode HS-STM

The performance of the  $r_j(t)/R_0$  STM preamplifier was also confirmed by our home-built HS-STM<sup>11</sup> We used parameters  $R_F = 10$  k $\Omega$ ,  $R_0 = 1$  k $\Omega$ , and  $C_{AF} = 0$  pF, and an OPA637 was used, resulting in a bandwidth of about 9 MHz, as mentioned above and as shown in Figs. 3(a) and 3(c). High-clarity atomic resolution images are obtained, which have almost the same quality as those obtained using the conventional STM preamplifier,<sup>35</sup> as shown in Figs. 4(a)–4(e). The frequency 9 MHz had broken the bandwidth record for an atomic resolution HS-STM.

The images, which were raw data of a highly oriented pyrolytic graphite (HOPG) sample, were obtained in air under room temperature with a mechanically cut Pt/Ir tip. The bias voltage was  $-220$  mV. The different brightness areas in the image may be caused by the obliqueness of the sample. One of the most noteworthy reflections of the performance of the STM system was the peak-peak voltage  $u_{pp} = 2U_A$ . The compromise magnitude in the line cut profile is  $u_{pp} \approx 140$  mV, as shown in Fig. 4(b). The 70 mV  $U_A$  indicates that the  $\text{SNR}_{\text{R0min}}$  is  $4.4 \times 10^3 \times N^{-1/2} U_A = 97$ , which means that the noise caused by  $R_0$  is not worth worrying about at all.

All the images in Fig. 4 were measured under a record-breaking frame rate of 250 frame/s<sup>4,9</sup> and a record-breaking line rate of 50 k



**FIG. 4.** The  $r_j(t)/R_0$  HS-STM image (raw data) based on the decompensated OPA. The sample is HOPG. (a) One frame HS-STM atomic resolution image (under conditions: 50 kHz fast scanning frequency, 250 Hz slow scanning frequency,  $7.5 \text{ \AA} \times 7.2 \text{ \AA}$ ). (b) Profile along the line AB in (a). About 150 mV  $u_{pp}$  is scaled to indicate the SNR of the STM system.  $U_B = -220$  mV. The lateral distance along the horizontal-axis is  $7.9 \text{ \AA}$ . (d) is the opposite frame in the same period with (c). The time difference  $\Delta t$  between (c) and (d) is 2 ms, which is half of the period. (e) is the image in the next half period of (d). The sine wave and the dotted lines in the atomic resolution images show the corresponding direction of scanning in the slow axis.

line/s;<sup>11,34</sup> both benefited from the unrestrained high bandwidth of the  $r_j(t)//R_0$  STM preamplifier.

A continuous scanning on the HOPG surface was also performed with a record-breaking slow axis scanning frequency of 250 Hz, as shown in Figs. 4(c)–4(e). There is little difference between each image. The frame frequency is twice as the scanning frequency to 500 Hz when counting the frames that are going back and forth, as shown in Figs. 4(c) and 4(d).

The 70 mV  $U_A$  indicates that the effective value of the tunneling current signal is  $U_A/\sqrt{2}R_F = 5 \mu\text{A}$ . This signal value means that the equivalent conductance of the tunneling junction is about  $0.3G_0$ , which indicates that this STM is operating under the quantum point contact state. QPCM can be applied to many fields of surface science. For example, the tribological characteristic, which is related to speed,<sup>35,36</sup> has been expressed in terms of current.<sup>37,38</sup> As for the open problem of application with a weak tunneling current, multi-stage amplification can be employed. This improvement is our next goal.

#### IV. CONCLUSION

The higher stability of the  $r_j(t)//R_0$  STM preamplifier was analyzed and testified, showing that it can increase the bandwidth. This research shows that a superior-performance, decompensated OPA can be used to further increase the bandwidth and the SNR of the STM preamplifier. The recording-break line rate and frame rate atomic resolution HS-STM images indicate that more interesting and important effects will be revealed. The  $r_j(t)//R_0$  method and decompensated OPA can also be generalized to almost all other types of STM preamplifiers to increase the SNR.

#### ACKNOWLEDGMENTS

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#### DATA AVAILABILITY

The data that support the findings of this study are openly available upon reasonable request.

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